

Search Notes



Application/Control No.

10/524,837

Examiner

Sang Y. Paik

Applicant(s)/Patent under Reexamination

MASHIMA ET AL.

Art Unit

3742

SEARCHED

Class	Subclass	Date	Examiner
219	443.1		
	444.1		
	465.1		
	466.1		
	467.1		
	468.1		
	468.2		
	544		
	546		
	547		
	548		
118	724		
	725	3/3/06	20

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East 765 JAPAN	3/3/06	20